

L Number	Hits	Search Text	DB	Time stamp
1	1	("5895264").PN.	USPAT; US-PGPUB	2003/10/20 11:10
2	0	korean with patent with "941273"	JPO; DERWENT	2003/10/20 11:11
3	0	korean with patent with "94-1273"	JPO; DERWENT	2003/10/20 11:12
4	0	"1994" and hyundai and (kim adj jae adj gap)	JPO; DERWENT	2003/10/20 11:14
5	0	"1994" and hyundai and (kim with jae with gap)	JPO; DERWENT	2003/10/20 11:14
6	0	"1994" and (hyundai adj electronics) and (kim with jae with gap)	JPO; DERWENT	2003/10/20 11:15
7	0	"1994" and hyundai and (kim adj jae adj gap)	USPAT; US-PGPUB	2003/10/20 11:15
8	0	"1994" and (hyundai adj electronics) and (kim with jae with gap)	USPAT	2003/10/20 11:15
9	0	(hyundai adj electronics) and (kim with jae with gap)	USPAT	2003/10/20 11:15
10	0	(hyundai adj electronics) and (kim with jae with gap)	US-PGPUB	2003/10/20 11:15
11	2748	438/637, 640, 672, 675.ccls.	USPAT; US-PGPUB	2003/10/20 11:47
12	1649	438/637, 640, 672, 675.ccls. and <19990916	USPAT; US-PGPUB	2003/10/20 11:48
13	5045	438/618, 253, 586, 595, 639, 672.ccls.	USPAT; US-PGPUB	2003/10/20 11:48
14	3072	438/618, 253, 586, 595, 639, 672.ccls. and <19990916	USPAT; US-PGPUB	2003/10/20 11:48
15	2299	(438/618, 253, 586, 595, 639, 672.ccls. and <19990916) not (438/637, 640, 672, 675.ccls. and <19990916)	USPAT; US-PGPUB	2003/10/20 12:44
16	16396	(samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))	USPAT; US-PGPUB	2003/10/20 13:02
17	1011	((samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))) and (contact adj hole)	USPAT; US-PGPUB	2003/10/20 13:02
18	343	((samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))) and (contact adj hole)) and opening	USPAT; US-PGPUB	2003/10/20 13:03
19	148	((samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))) and (contact adj hole)) and opening) and <19990916	USPAT; US-PGPUB	2003/10/20 12:58
20	113600	(samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))	EPO; JPO; DERWENT	2003/10/20 13:02
21	1187	((samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))) and (contact adj hole)	EPO; JPO; DERWENT	2003/10/20 13:03
22	80	((samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))) and (contact adj hole)) and opening	EPO; JPO; DERWENT	2003/10/20 13:03

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